## Application/Control No. Applicant(s)/Patent Under Reexamination HUENIKEN ET AL. Examiner Chandrika Prasad Application/Control No. Applicant(s)/Patent Under Reexamination HUENIKEN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	Α	US-6045384	04-2000	Norizuki et al.	439	310
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